

<b>Notice of References Cited</b>	Application/Control No. 10/789,706		Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner Kirsten C Jolley		Art Unit 1762	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,858,475	01-1999	Chiu, Wei-Kay	427/560
	B	US-5,609,995	03-1997	Akram et al.	430/327
	C	US-6,635,113	10-2003	Takamori et al.	118/681
	D	US-5,798,140	08-1998	Parodi et al.	427/240
	E	US-2003/0053015	03-2003	Minoura et al.	349/113
	F	US-6,616,760	09-2003	Kitano et al.	118/302
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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